Calculation of electronic and transport properties of single-walled boron nanotubes

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Materials and methods

In this work, the SIESTA 4.1 software package is for geometry used relaxation, searching for potential the energy minimum, and calculating the electronic properties We nanostructures. ot used a Density Functional Theory (DFT) base set with Generalized Gradient (GGA) Approximation Purdue-Burkand Ernzerhoff (PBE) parameterization because calculation these performed parameters both terms of in well calculation accuracy and calculation time. The force acting on each atom after relaxation was set to 0.04 eV/Å, and the energy limit was chosen to be 350 Ry. The Brillouin zone was sampled by a 1 × 1 × 36 Monkhorst-Pack grid. relaxation process The was performed by the Broyden algorithm and the Pulay corrections.



JT	-5.188	-6.049	13
	-5.808	-6.019	
Γ	-5.124	-6.034] 4

Conclusions

this poster presentation In presents equilibrium atomistic models of single-walled boron nanotubes obtained using the first-principles SIESTA code. Atomistic models of boron nanotubes were obtained by twisting monolayer sheets of borophene (triangulated, beta and hi-3 topologies) followed by geometric relaxation of coordinates atomic and translation vectors. The results of the calculation of the density of electronic states (DOS) showed the absence of a band gap for all considered cases, as well as a negative value of the formation energy. At the same time, using the nonequilibrium Green-Keldysh functions, electron the functions transmission were obtained all the for considered structures, where a boron nanotube composed of triangulated borophene in the "zigzag" direction showed an extremely low resistance value equal to 457 Ohm and a formation energy equal to -6.019 eV. This study makes it possible to judge the applicability boron of nanotubes as low-dimensional conductors in nano- and microelectronics.